

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

IFW

In re the Application of

Inventors: Kenichiro SHINOI, et al.

Application No.: 10/542,611

Filed: OIPE UNIT  
July 18, 2005

For: NOV 16 2006  
ACCURACY MEASUREMENT APPARATUS AND ACCURACY  
MEASUREMENT METHOD FOR CHANNEL QUALITY REPORT

INFORMATION DISCLOSURE STATEMENT

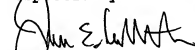
Assistant Commissioner of Patents  
Washington, DC 20231

Dear Sir:

Pursuant to Rules 56 and 99, Applicants hereby call the attention of the Patent Office to the art listed on the attached Form PTO 1449. This reference was cited in a Korean Office Action dated September 25, 2006 (copy attached). US '195 corresponds to KR '333.

Applicants present this art so that the Patent Office may, in the first instance, determine any relevancy thereof to the presently claimed invention, see Beckman Instruments, Inc. v. Chemtronics, Inc., 439 F.2d 1369, 1380, 165 USPQ 355, 364 (5th Cir. 1970). Also see Patent Office Rules 104 and 106. Applicants respectfully request that this art be expressly considered during the prosecution of this application and made of record herein and appear among the "References Cited" on any patent to issue herefrom.

Respectfully submitted,



James E. Ledbetter  
Registration No. 28,732

Date: November 16, 2006

JEL/ejw  
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